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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/647,258	NISHIMURA ET AL.	•
Examiner	Art Unit	
James Mackey	1722	

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Class	Subclass	Date	Examiner
425	190, 192R, 589, 595	9/20/2005	JPM
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SEARCH NOT (INCLUDING SEARCH	'ES STRATEGY)
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Conducted INVENTOR name search in IFW	9/20/2005	· JPM
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